

Notice of References Cited	Application/Control No. 10/076,485	Applicant(s)/Patent Under Reexamination YABUKI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 9-213302	08-1997	Japan	Sato et al.	H01M 2/30
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NON-PATENT DOCUMENTS

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